




# TEST REPORT

**Application No.....:** S202206210437  
**Applicant's name.....:** CHI ZHOU PADAUK ELECTRONICS TECHNOLOGY CO.,LTD  
**Applicant's address :** 3rd Floor, Building 6, Electronic Information Park, Economic and Technological Development Area, Chizhou, Anhui  
**Sample description: :** Touch Key Demo Board  
**Model.....:** PFC460

**Date of receipt of test item.....:** 2022.06.16  
**Test location.....:** G9 building, China Sensor Network International innovation Park, No.200, Linghu Ave, new district of Wuxi, China  
**Test standard.....:** IEC 61000-4-6:2013 Electromagnetic compatibility (EMC) – Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields

**Test date(s).....:** 2022.06.16  
**Test result.....:** The test results are in compliance with the above mentioned standards.  
**Date of issue.....:** 2022.06.29

<b>Compiled by:</b>	<b>Reviewed by:</b>	<b>Approved by:</b>
Amos Xia	Line Chen	Zeming Zhang / Manager
		



**Other aspects:** N/A

**Abbreviations:** P = passed; F = failed; N/A = not applicable

The test result in this test report refers exclusively to the presented test sample. This report shall not be reproduced, except in full, without the written approval of FGTEST.

In China, this test report is only used for scientific research, teaching or internal quality control if there is no China Metrology Accreditation (CMA) mark.



<b>Test item description..:</b>	Touch Key Demo Board
<b>Trade mark.....:</b>	/
<b>Manufacturer.....:</b>	CHI ZHOU PADAUK ELECTRONICS TECHNOLOGY CO.,LTD
<b>Manufacturer's address .....:</b>	3rd Floor, Building 6, Electronic Information Park, Economic and Technological Development Area, Chizhou, Anhui
<b>Factory.....:</b>	CHI ZHOU PADAUK ELECTRONICS TECHNOLOGY CO.,LTD
<b>Factory's address.....:</b>	3rd Floor, Building 6, Electronic Information Park, Economic and Technological Development Area, Chizhou, Anhui
<b>Ratings.....:</b>	Input: AC 220V, 50Hz



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## 1. TEST RESULT SUMMARY

Test Standard	Test Item	Test Method	Result (Pass/Fail)
<b>Immunity Measurements</b>			
IEC 61000-4-6:2013	Radio-Frequency Common Mode	IEC 61000-4-6	Pass

## 2. GENERAL DESCRIPTION OF EUT

### 2.1 BASIC DESCRIPTION OF EQUIPMENT UNDER TEST

Equipment:	Touch Key Demo Board
Model No.:	PFC460
Power Supply Rating:	Input: AC 220V, 50Hz
Sample submitting way:	<input checked="" type="checkbox"/> Provided by customer <input type="checkbox"/> Sampling

### 2.2 EUT TEST MODE

Test mode:	Mode 1: Normal working.
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### 3. LIST OF USED TEST EQUIPMENT

Name of Equipment	Manufacturer	Model	Calibration Due
Conducted Immunity Test(CS)			
Signal Generator	TESEQ	NSG 4070-35	2023-01-18
Attenuator	TESEQ	ATN 6050	2022-12-21
CDN	TESEQ	CDN M016	2022-12-12

## 4. IMMUNITY TEST

### 4.1 INJECTED CURRENTS SUSCEPTIBILITY TEST

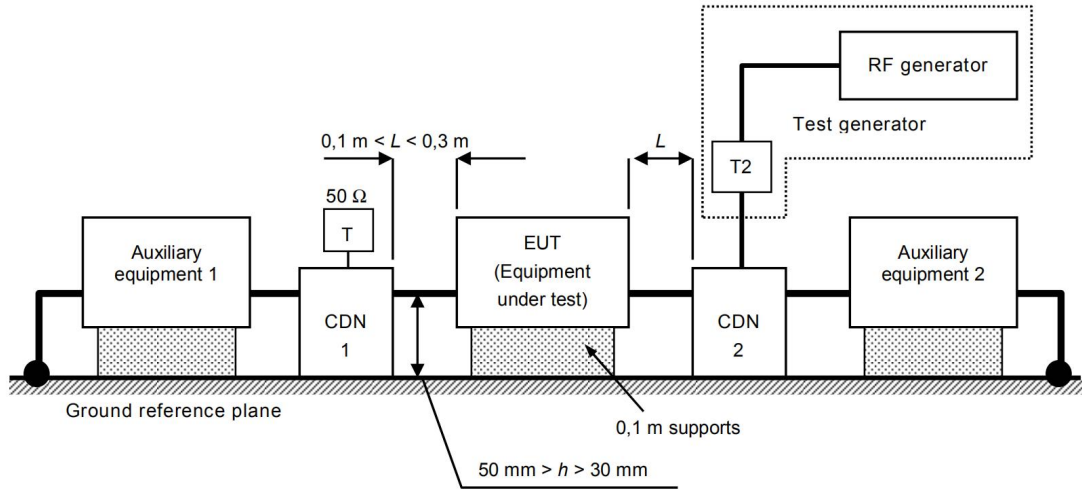
#### 4.1.1 TEST SPECIFICATION

Basic Standard	IEC 61000-4-6
Frequency Range	0.15 MHz~80 MHz
Field Strength	10V
Modulation	1kHz, 80% AM
Frequency Step	1%
Dwell Time	1s

#### 4.1.2 TEST PROCEDURE

- 1) Set up the EUT, CDN and test generators as shown on Section 4.1.3
- 2) Let the EUT work in test mode and measure it.
- 3) The EUT are placed on an insulating support 0.1m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane about 0.3m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
- 4) The disturbance signal described below is injected to EUT through CDN.
- 5) The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 6) The frequency range is swept from 150 kHz to 80MHz using above signal level, and with the disturbance signal 80% amplitude modulated with a 1 kHz sine wave.
- 7) Where the frequency is swept incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- 8) Recording the EUT operating situation during compliance testing and decide the EUT immunity criterion.

### 4.1.3 TEST SETUP







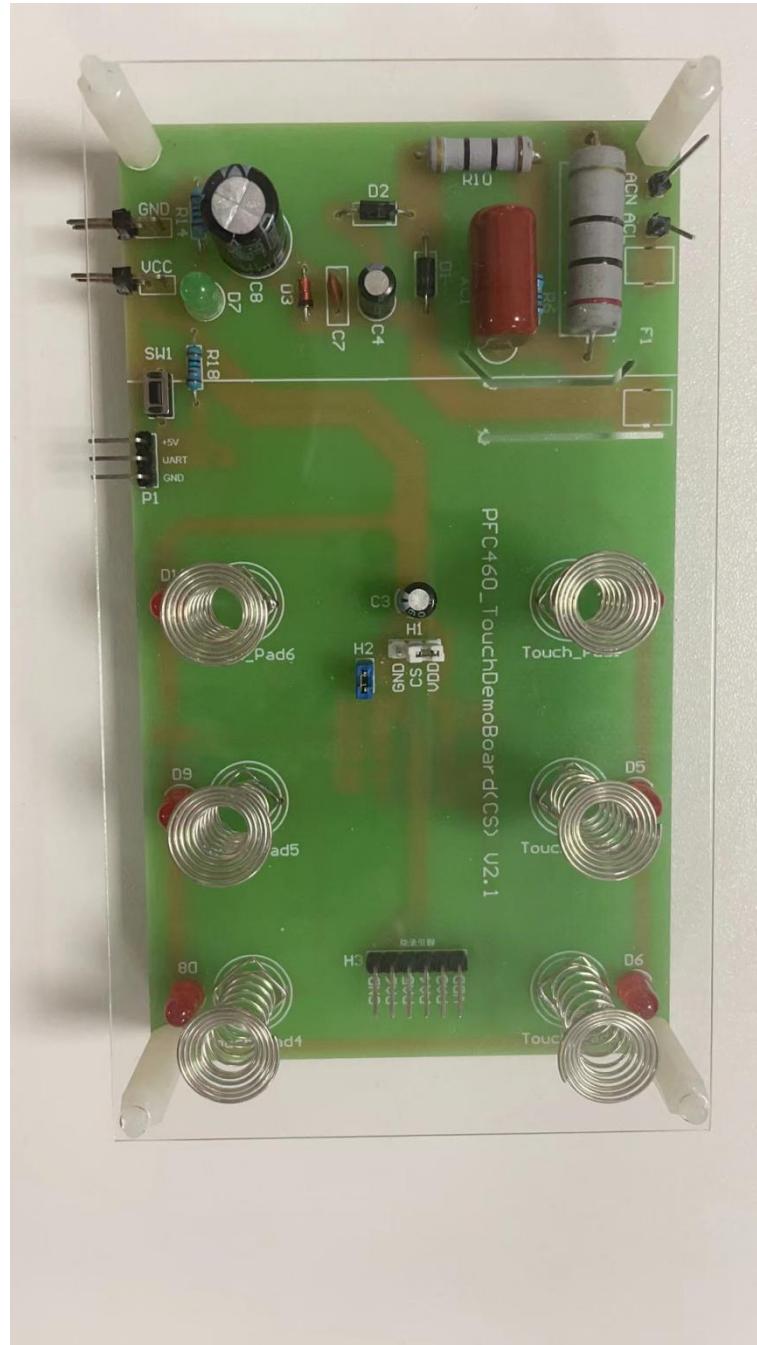
#### 4.1.4 TEST RESULTS

EUT Name:	Touch Key Demo Board	Model:	PFC460
Test Mode:	Mode 1	Environmental Conditions:	23.0°C55%RH101kPa
Test Date:	2022-06-16	Tested By:	Kinnal Feng

Frequency Band (MHz)	Field Strength (V.rms)	Cable	Injection Method	Required Performance	Actual performance	Result (P/F)
0.15-80	10	AC port	CDN	Criterion A	Criterion A <sup>a)</sup>	PASS

**NOTE:** <sup>a)</sup> There was no change compared with initial operation during the test.

## APPENDIX A. PHOTOGRAPHS OF EUT



General view

## APPENDIX B: PHOTOGRAPH OF THE TEST ARRANGEMENT



CS

## APPENDIX C: PERFORMANCE CRITERIA

<p><b>Criteria A</b></p>	<p>During and after the test the EUT shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a minimum performance level specified by the manufacturer when the EUT is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the EUT if used as intended.</p>
<p><b>Criteria B</b></p>	<p>After the test, the EUT shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the EUT is used as intended. The performance level may be replaced by a permissible loss of performance.</p> <p>During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.</p> <p>If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the EUT if used as intended.</p>
<p><b>Criteria C</b></p>	<p>During and after testing, a temporary loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls or cycling of the power to the EUT by the user in accordance with the manufacturer's instructions.</p> <p>Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.</p>

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